

Description

The G16N03 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

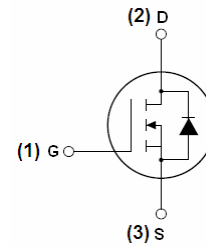
General Features

| VDSS | RDS(ON) @10V (typ) | RDS(ON) @4.5V (typ) | ID |
|------|-----------------------|------------------------|-----|
| 30V | 7mΩ | 10.5mΩ | 16A |

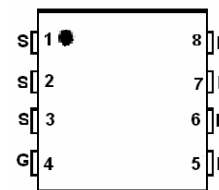
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

Application

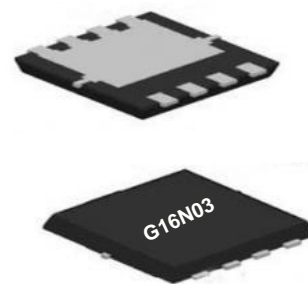
- SMPS and general purpose applications
- Hard switched and high frequency circuits
- Uninterruptible power supply



Schematic diagram



Marking and pin assignment



DFN 5x6

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

| Parameter | Symbol | Limit | Unit |
|-----------------------------------------------------|--------------------------|------------|---------------------|
| Drain-Source Voltage | V_{DS} | 30 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Drain Current-Continuous | I_D | 16 | A |
| Drain Current-Continuous($T_C=100^\circ\text{C}$) | $I_D(100^\circ\text{C})$ | 11 | A |
| Pulsed Drain Current | I_{DM} | 50 | A |
| Maximum Power Dissipation | P_D | 30 | W |
| Derating factor | | 0.24 | W/ $^\circ\text{C}$ |
| Single pulse avalanche energy ^(Note 5) | E_{AS} | 70 | mJ |
| Operating Junction and Storage Temperature Range | T_J, T_{STG} | -55 To 150 | $^\circ\text{C}$ |

Thermal Characteristic

| | | | |
|----------------------------------------------------------|-----------------|-----|------|
| Thermal Resistance, Junction-to-Case ^(Note 2) | $R_{\theta JC}$ | 4.2 | °C/W |
|----------------------------------------------------------|-----------------|-----|------|

Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise noted)

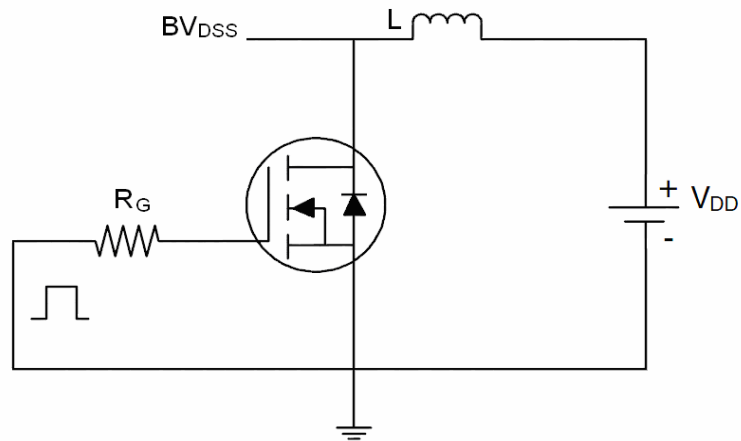
| Parameter | Symbol | Condition | Min | Typ | Max | Unit |
|------------------------------------------------------|--------------|---------------------------------------------------------------------------------|-----|------|-----------|------------|
| Off Characteristics | | | | | | |
| Drain-Source Breakdown Voltage | BV_{DSS} | $V_{GS}=0V, I_D=250\mu A$ | 30 | 36 | - | V |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS}=30V, V_{GS}=0V$ | - | - | 1 | μA |
| Gate-Body Leakage Current | I_{GSS} | $V_{GS}=\pm 20V, V_{DS}=0V$ | - | - | ± 100 | nA |
| On Characteristics ^(Note 3) | | | | | | |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS}, I_D=250\mu A$ | 1 | 1.6 | 3 | V |
| Drain-Source On-State Resistance | $R_{DS(on)}$ | $V_{GS}=10V, I_D=10A$ | - | 7.0 | 9 | m Ω |
| | | $V_{GS}=4.5V, I_D=10A$ | - | 10.5 | 14 | |
| Forward Transconductance | g_{FS} | $V_{DS}=5V, I_D=8A$ | 15 | - | - | S |
| Dynamic Characteristics ^(Note 4) | | | | | | |
| Input Capacitance | C_{iss} | $V_{DS}=15V, V_{GS}=0V,$ $F=1.0\text{MHz}$ | - | 1530 | - | PF |
| Output Capacitance | C_{oss} | | - | 250 | - | PF |
| Reverse Transfer Capacitance | C_{rss} | | - | 198 | - | PF |
| Switching Characteristics ^(Note 4) | | | | | | |
| Turn-on Delay Time | $t_{d(on)}$ | $V_{DD}=15V, I_D=10A$ $V_{GS}=10V, R_{GEN}=1.8\Omega$ | - | 10 | - | nS |
| Turn-on Rise Time | t_r | | - | 8 | - | nS |
| Turn-Off Delay Time | $t_{d(off)}$ | | - | 30 | - | nS |
| Turn-Off Fall Time | t_f | | - | 5 | - | nS |
| Total Gate Charge | Q_g | $V_{DS}=15V, I_D=9A,$ $V_{GS}=10V$ | - | 15 | - | nC |
| Gate-Source Charge | Q_{gs} | | - | 3 | - | nC |
| Gate-Drain Charge | Q_{gd} | | - | 4.5 | - | nC |
| Drain-Source Diode Characteristics | | | | | | |
| Diode Forward Voltage ^(Note 3) | V_{SD} | $V_{GS}=0V, I_S=10A$ | - | 0.85 | 1.2 | V |
| Diode Forward Current ^(Note 2) | I_S | | - | - | 25 | A |
| Reverse Recovery Time | t_{rr} | $T_J = 25^\circ\text{C}, I_F = 10A$ $di/dt = 100A/\mu s$ ^(Note 3) | - | 22 | 35 | nS |
| Reverse Recovery Charge | Q_{rr} | | - | 12 | 20 | nC |
| Forward Turn-On Time | t_{on} | Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD) | | | | |

Notes:

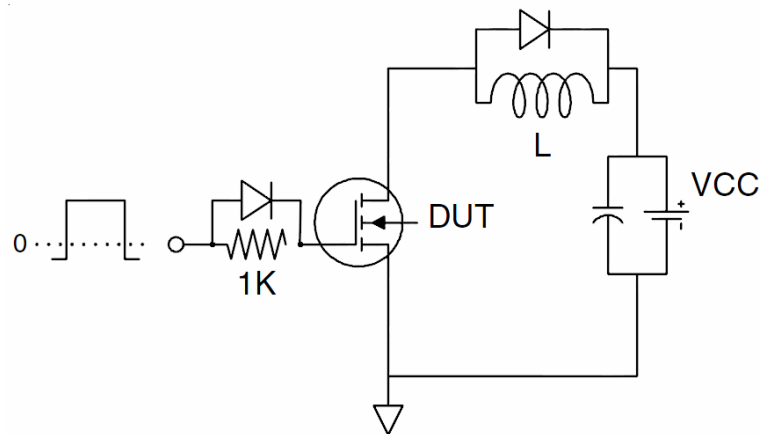
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production
5. EAS condition: $T_J=25^\circ\text{C}, V_{DD}=15V, V_G=10V, L=0.1\text{mH}, R_g=25\Omega$

Test Circuit

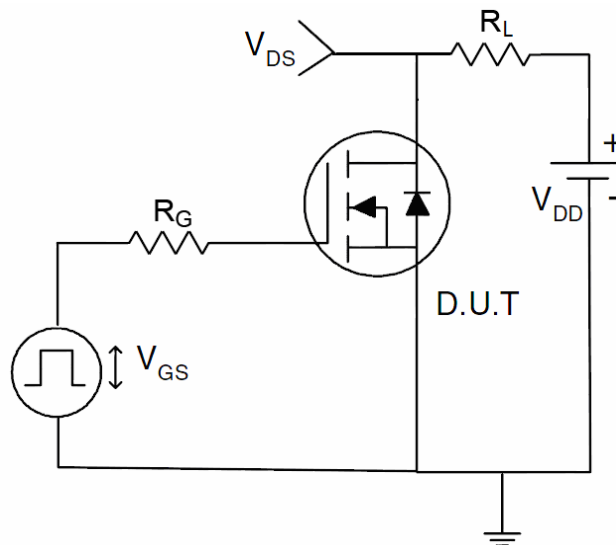
1) E_{AS} Test Circuits



2) Gate Charge Test Circuit:



3) Switch Time Test Circuit:



Typical Electrical and Thermal Characteristics (Curves)

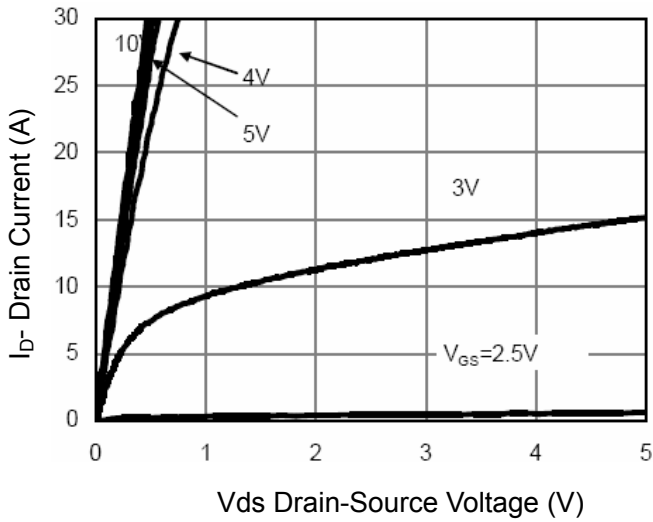


Figure 1 Output Characteristics

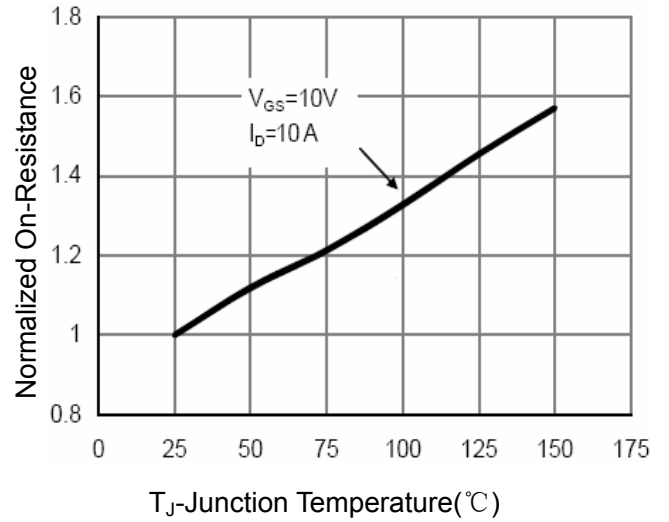


Figure 4 R_{dson} -Junction Temperature

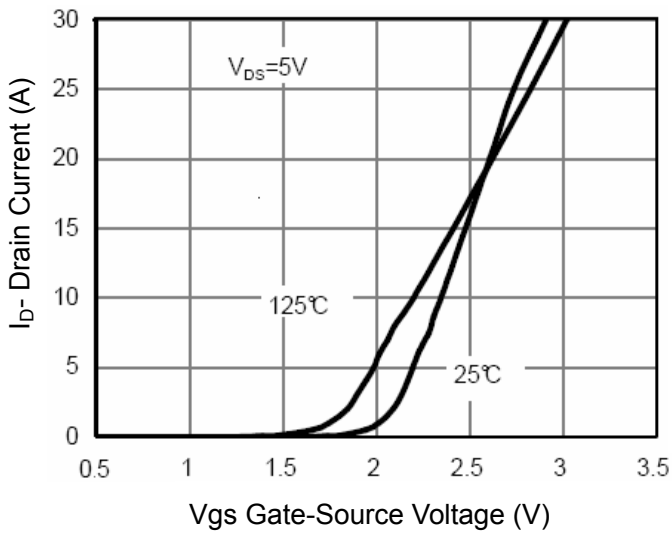


Figure 2 Transfer Characteristics

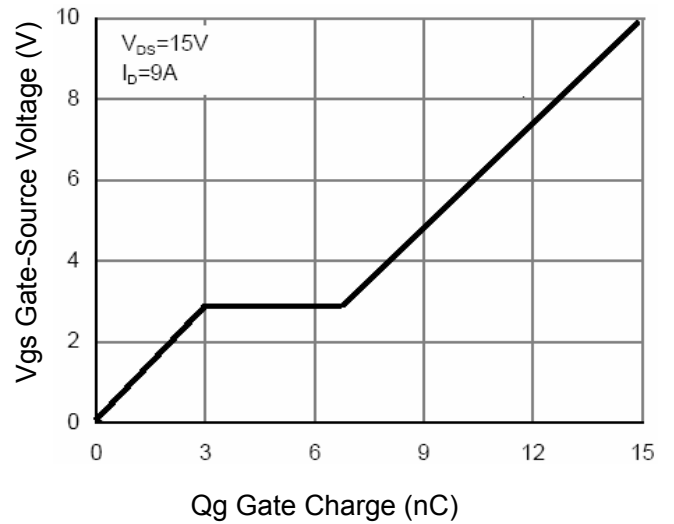


Figure 5 Gate Charge

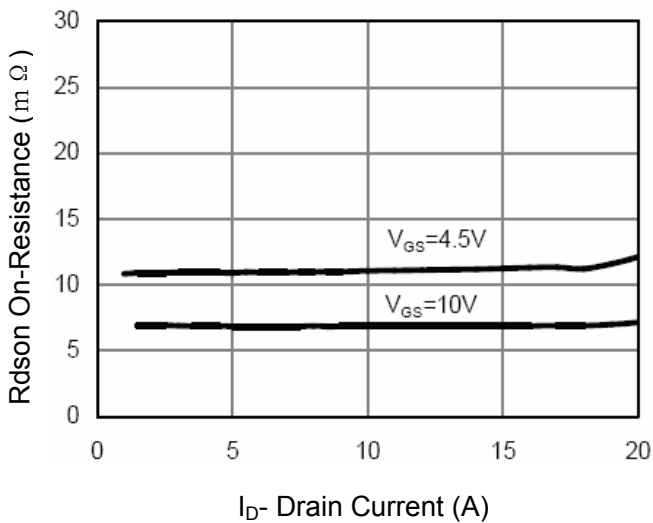


Figure 3 R_{dson} - Drain Current

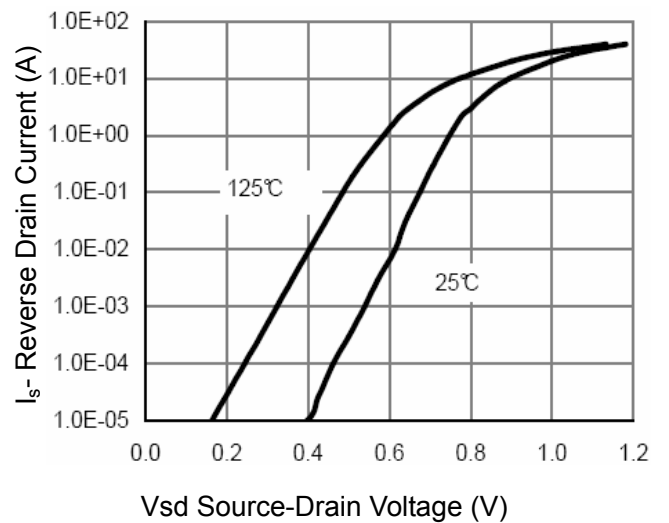
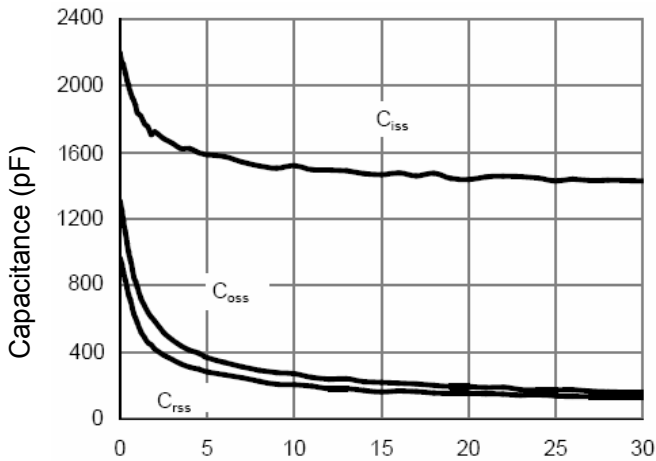
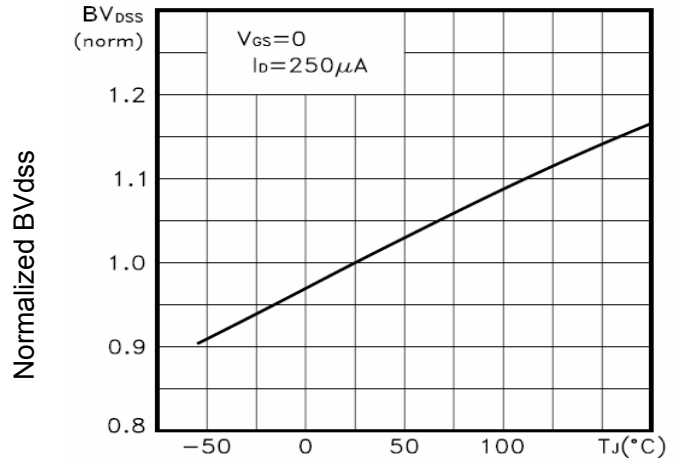


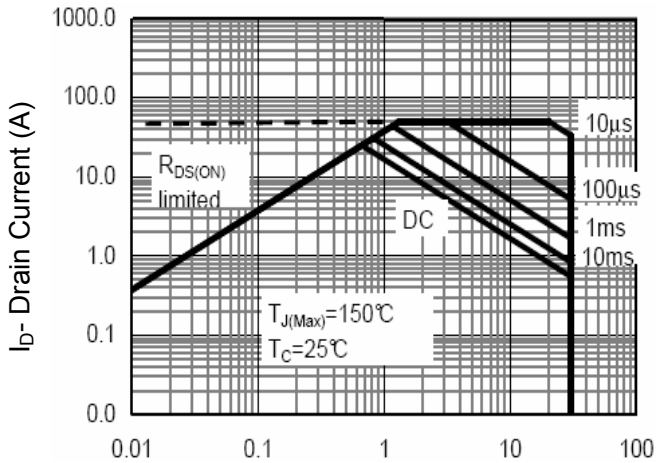
Figure 6 Source- Drain Diode Forward



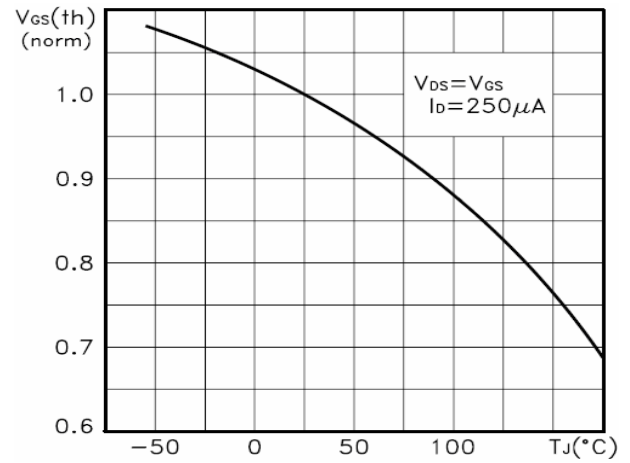
Vds Drain-Source Voltage (V)
Figure 7 Capacitance vs Vds



T_J-Junction Temperature(°C)
Figure 9 BV_{DSS} vs Junction Temperature



Vds Drain-Source Voltage (V)
Figure 8 Safe Operation Area



T_J-Junction Temperature(°C)
Figure 10 V_{GS(th)} vs Junction Temperature

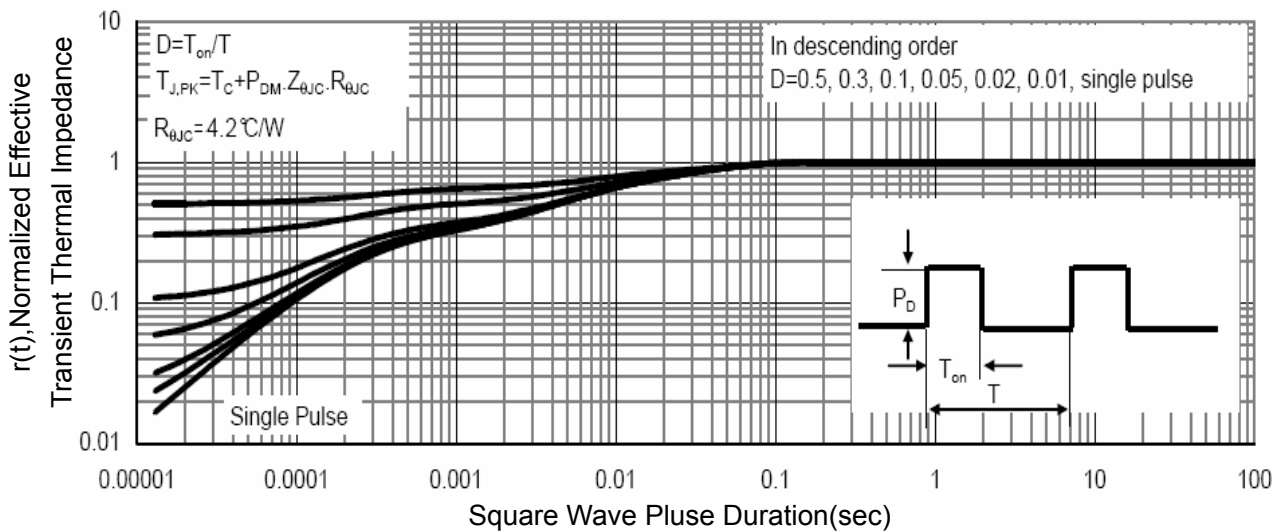


Figure 11 Normalized Maximum Transient Thermal Impedance